Amendments to the Specification:

Please replace the paragraph at page 1, lines 3-10 with the following amended paragraph:

This application is a divisional of U.S. Serial No. ~~10/123,228~~ 10/123,028, filed April 12, 2002, now U.S. Patent No. 6,921,497 which is a continuation-in-part of U.S. Serial No. 09/416,720, filed October 13, 1999, now U.S. Patent No. 6,572,792, issued June 3, 2003, and a continuation-in-part of International Application No. PCT/US00/28549, which designated the United States and was filed on October 13, 2000, published in English, which is a continuation of U.S. Serial No. 09/416,720, filed October 13, 1999. The entire teachings of the above applications are incorporated herein by reference.

10-13

Please replace the paragraphs at page 34, lines ~~16-19~~ with the following amended paragraphs:

An x-ray fluorescence analysis of the copper sample is provided in Figure [[26]] 25, with the K_α peak of a copper control standard shown for reference.

An x-ray fluorescence analysis of the copper sample is provided in Figure [[27]] 26, with the K_α peak of an aluminum control standard shown for reference.

5-15

Please replace the paragraphs at page 37, lines ~~11-21~~ with the following amended paragraph:

An x-ray fluorescence analysis of the nickel sample is provided in Figures [[28A]] 27A and [[28B]] 27B, with the K_α and L_α peaks of a nickel control standard shown for reference.

An x-ray fluorescence analysis of the nickel sample is provided in Figure [[29A]] 28A, with the K_α peak of an aluminum control standard shown for reference.

An x-ray fluorescence analysis of the nickel sample is provided in Figure [[29B]] 28B, with the K_α peak of a zirconium control standard shown for reference.

An x-ray fluorescence analysis of the nickel sample is provided in Figure [[30A]] 29, with the K_α peak of a sulfur control standard shown for reference.